

Design and Performance Evaluation of the Silicon Strip Detector Cooling System for J-PARC Muon g-2/EDM Experiment

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and J-PARC muon g-2/EDM Collaboration

J-PARC muon $g - 2$ /EDM Experiment

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Anomalous magnetic moment ($g-2$)

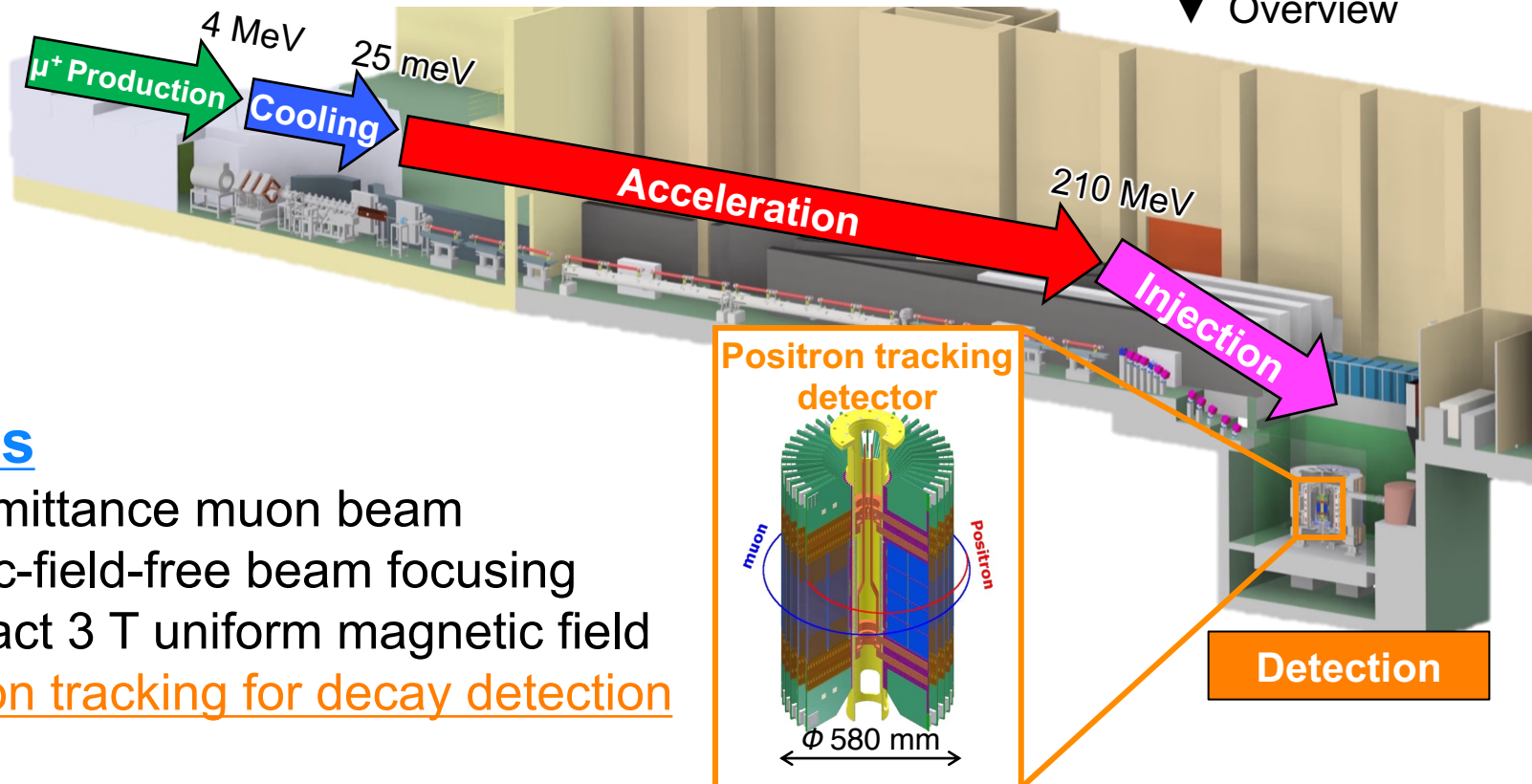
- Experimental value: 0.12ppm (FNAL)
- Discrepancy with the Standard Model — Unresolved... dependent on HVP
- ~ 0.1 ppm independent measurement

Electric dipole moment (EDM)

- Time-reversal violation \rightarrow CP violation
- Experimental upper limit: $\sim 10^{-19}$ e \cdot cm
- \gg Theoretical prediction: $\sim 10^{-38}$ e \cdot cm
- Target sensitivity: 10^{-21} e \cdot cm

Verification of muon $g-2$ and enhancing muon EDM sensitivity

▼ Overview



Features

- Low-emittance muon beam
- Electric-field-free beam focusing
- Compact 3 T uniform magnetic field
- Positron tracking for decay detection

Positron tracking detector

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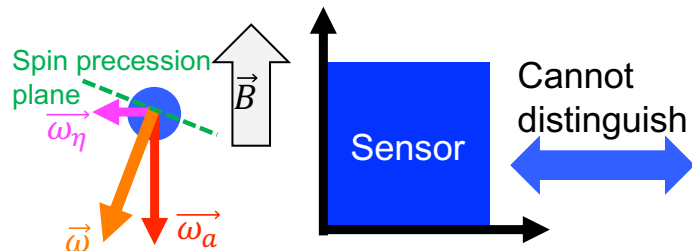
Detector Design & Requirements

- e^+ trajectory reconstruction via (t, x)
- 40 “Vane” radial configuration
- Operating in **3 T field & vacuum (0.1 atm)**

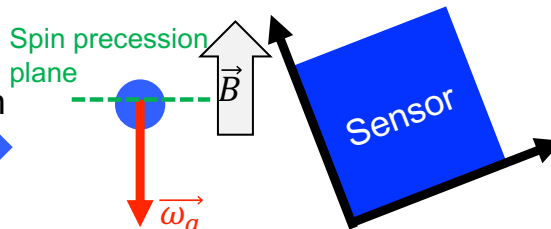
EDM Systematic Uncertainties & Alignment

Manage Misalignment (Major Error)

A system with a finite EDM as seen from a normal sensor



A system with EDM = 0 as seen from a tilted sensor

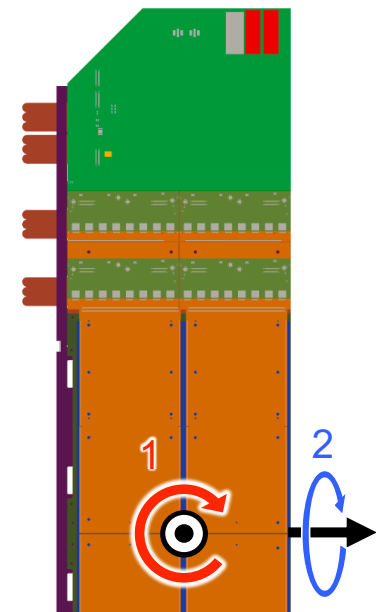
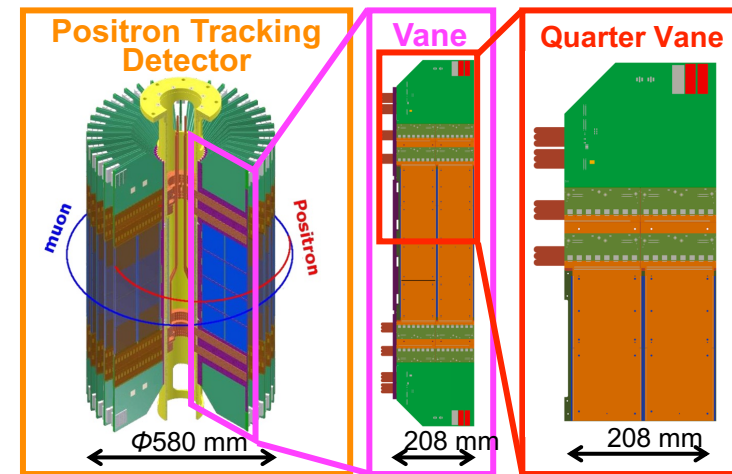


Systematics control & mitigation

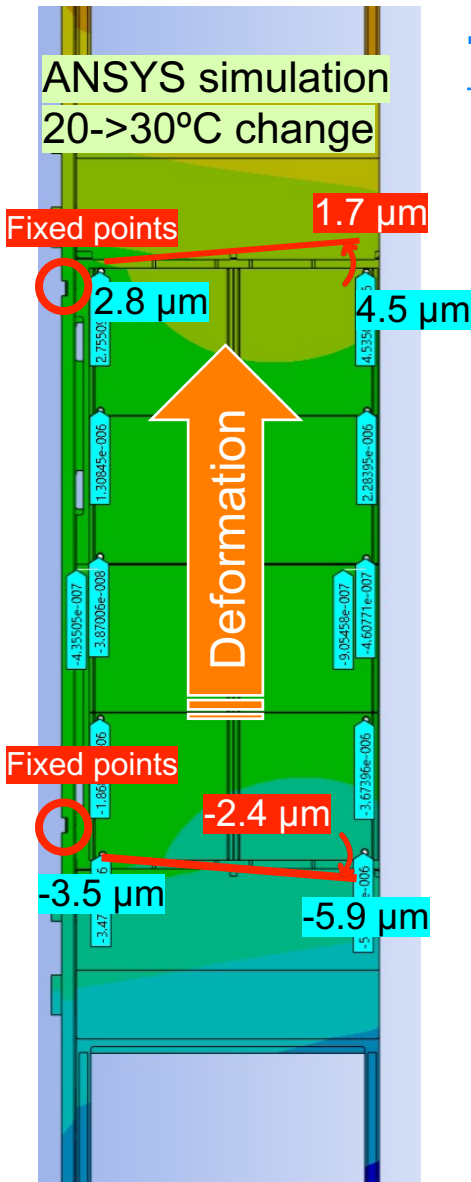
- Assembly with CMM metrology
- Thermal stabilization to minimize deformation effects
- Laser alignment monitor & Track-based alignment

Required tolerances for 10^{-21} e·cm

1. **Vane plane rotation: ~ 10 μ rad**
2. **Vane thickness rotation: ~ 200 μ rad**



Thermal Stability & Alignment Requirements 4/9



Tolerance vs. Deformation

■ **Alignment Requirement: 2 μm** (20 cm \times 10 μrad)

■ **Thermal Deformation: 2.4 μm**

(Expected total rotational displacement for a $\Delta T=10$ °C global change)

① **Steady-state Deformation (measurable)**

- Monitored via the Alignment System
- Rotational components analyzed through simulations

Requirement: Vane plane rotation ~ 10 μrad

② **Short-timescale Deformation (Unmeasurable)**

- Caused by temperature fluctuations; a primary source of misalignment
- Mitigation: Requires strict thermal stabilization

2 μm Alignment Requirement $\rightarrow \Delta T < 8.3$ °C

Cooling System Design

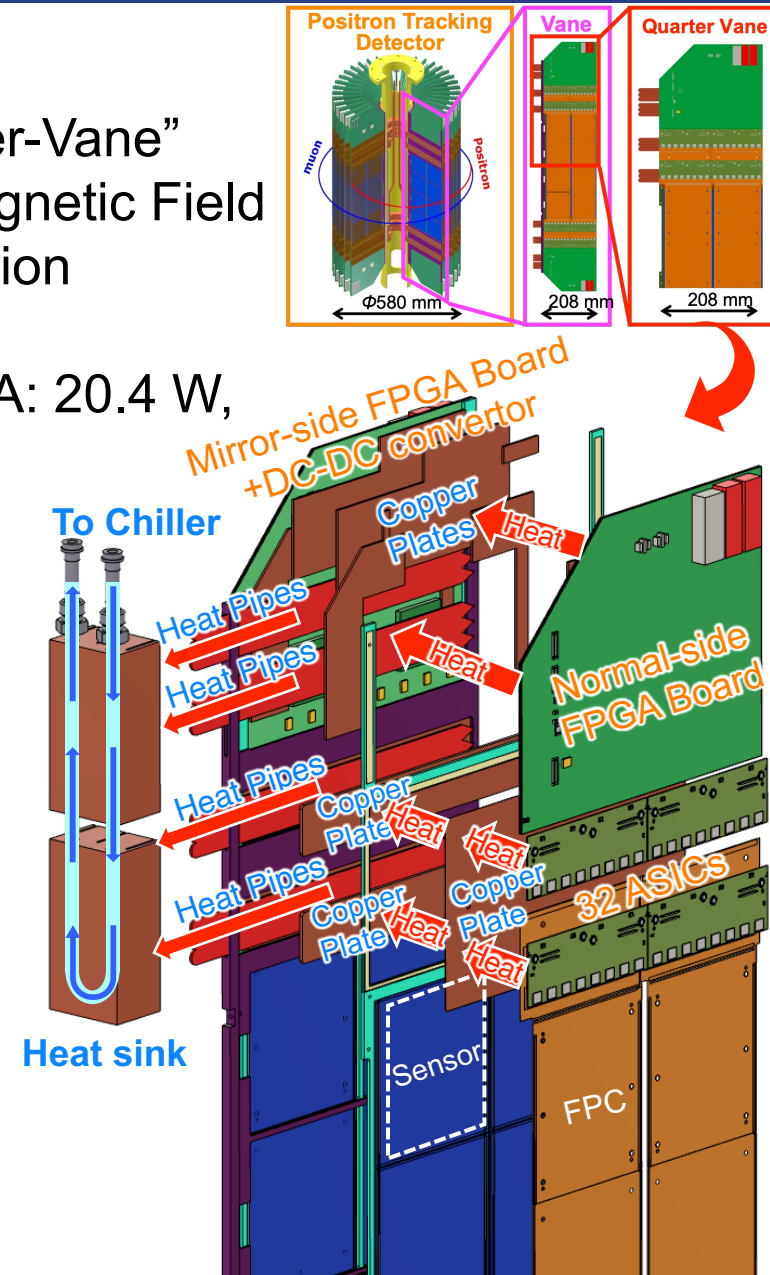
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Requirements

- Compact: **Thickness < 3 mm** per “Quarter-Vane”
- Environment: Vacuum (0.1 atm) & 3 T Magnetic Field
- Material: Non-magnetic Copper Construction
- Total heat load: **8.5 kW (160 Q-Vane)**
 - **Q-Vane: 53.6 W** (ASIC: 28.2 W, FPGA: 20.4 W, DC-DC converter: 5 W)
- Temperature Stability: IC thermal safety & sensor deformation control

Structure

- Heat Pipes: High-conduction ($\sim 100\times$ Cu) from FPGA/ASIC to heat sink
- Copper Plates: Ensure heat paths to heat pipes
- Heat Sink: Constant 10 °C (water-cooled by external chiller)

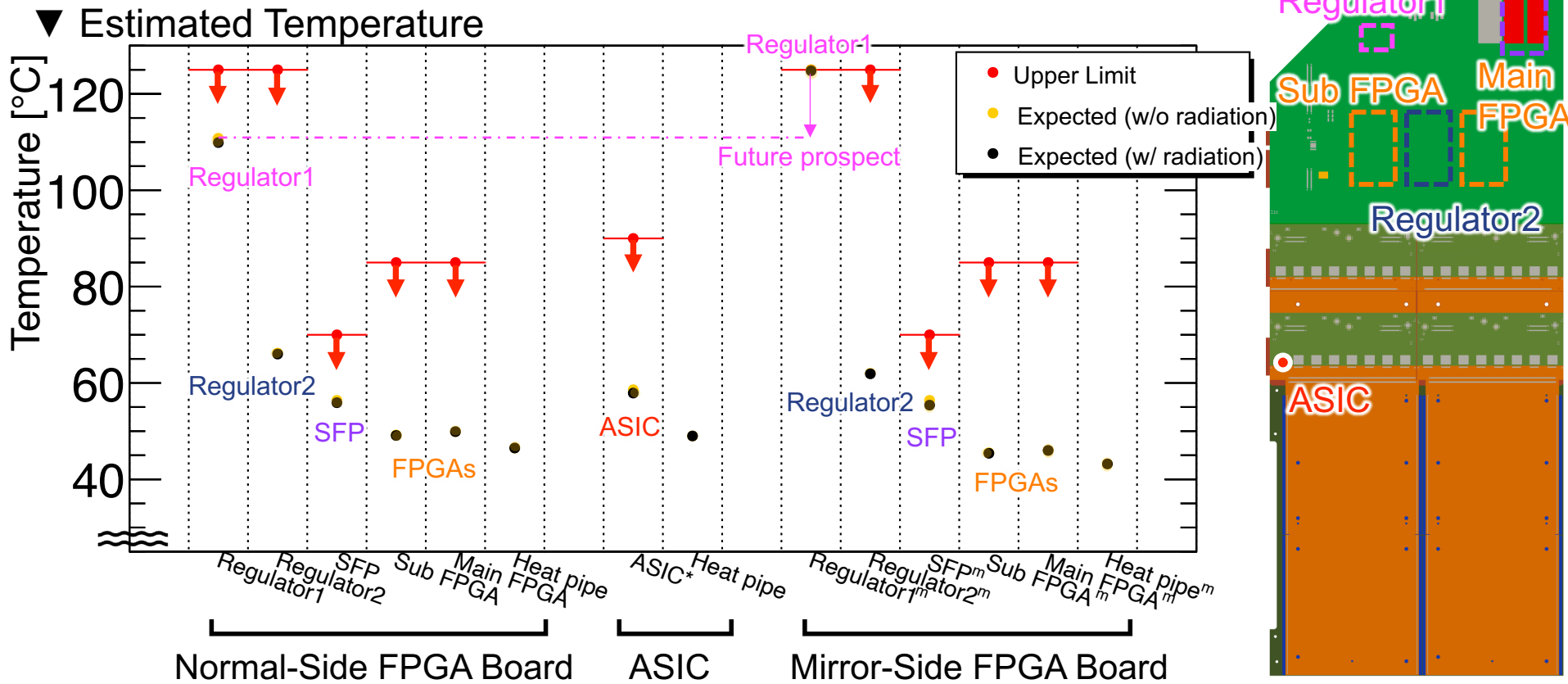


Simulation Results in Real Operation

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Estimated Temperature by Simulation (ANSYS) in 40-Vane Real Configuration

- **IC Safety: All ICs cooled below operational limits**
- **Thermal Deformation: 6.2 μrad (<10 μrad : Requirement)**



Critical Point: Tightest margin at Mirror-Side Regulator1

- Layout optimization matches Mirror-Side cooling performance to Normal-Side

Cooling Test in Vacuum

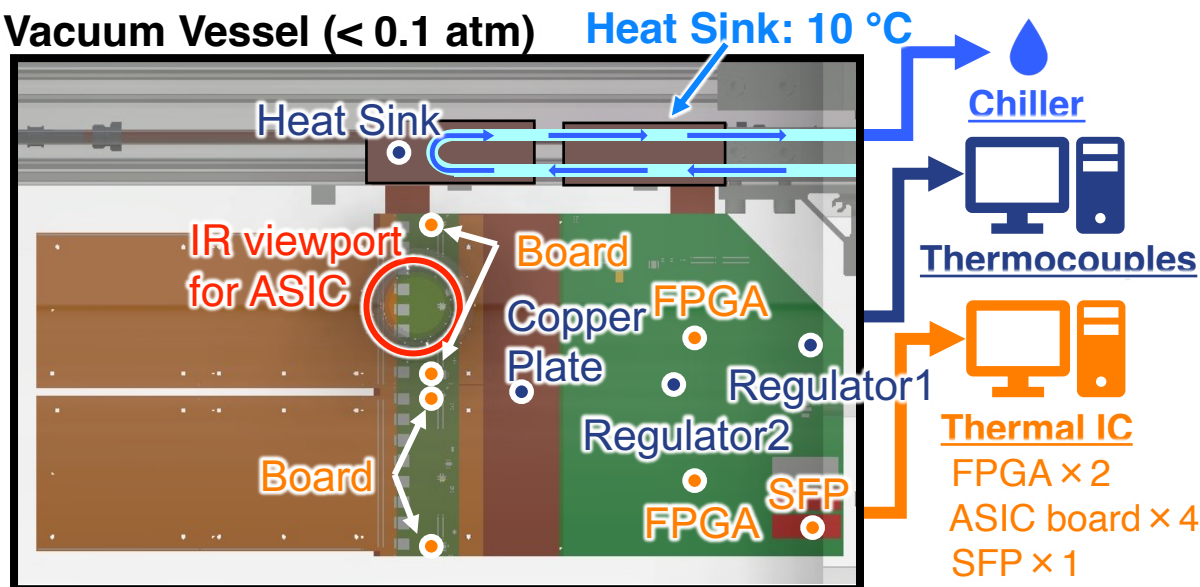
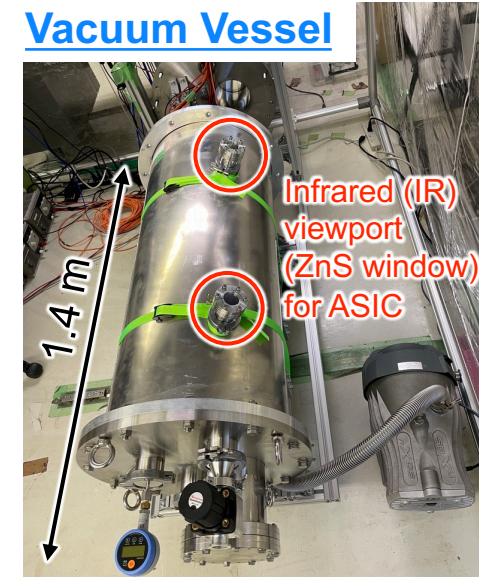
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Validated cooling system functionality in a vacuum environment equivalent to real operation

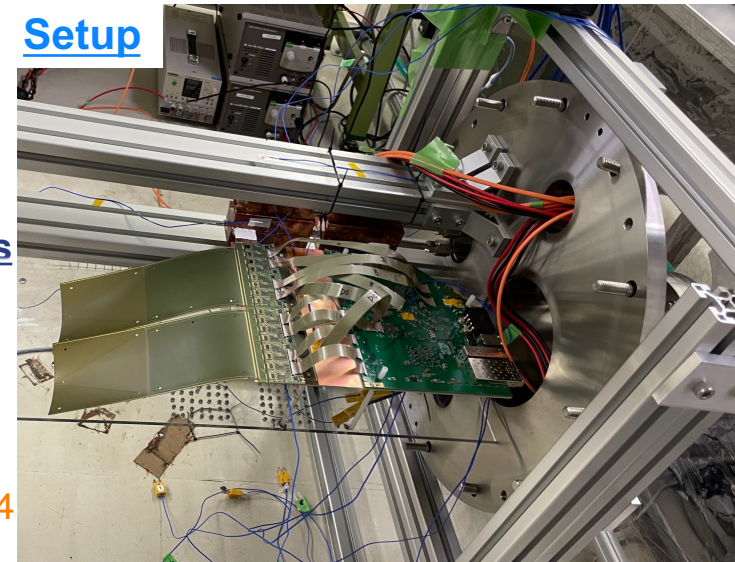
Experimental Setup

- Components: FPGA board + 16 ASICs
(No DC-DC converters or sensors)
- Heat Load: Identical to real-operation power levels
- Vacuum Level: 4.3×10^{-2} atm
- Coolant: Water-cooled at 10 °C via external chiller
- Radiation effects are evaluated via simulation

Vacuum Vessel



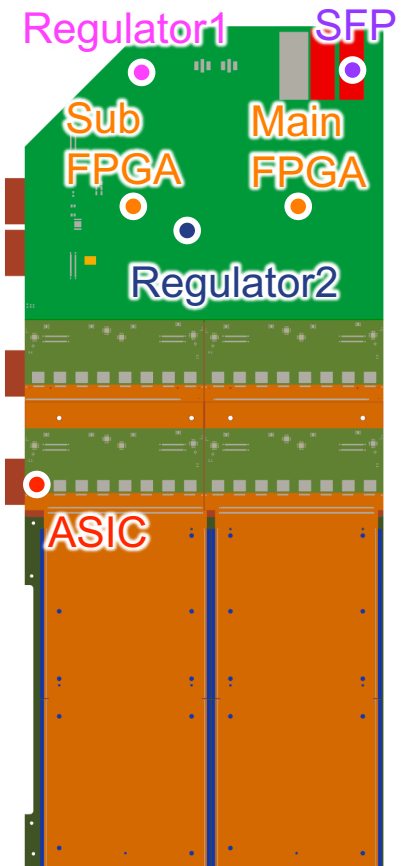
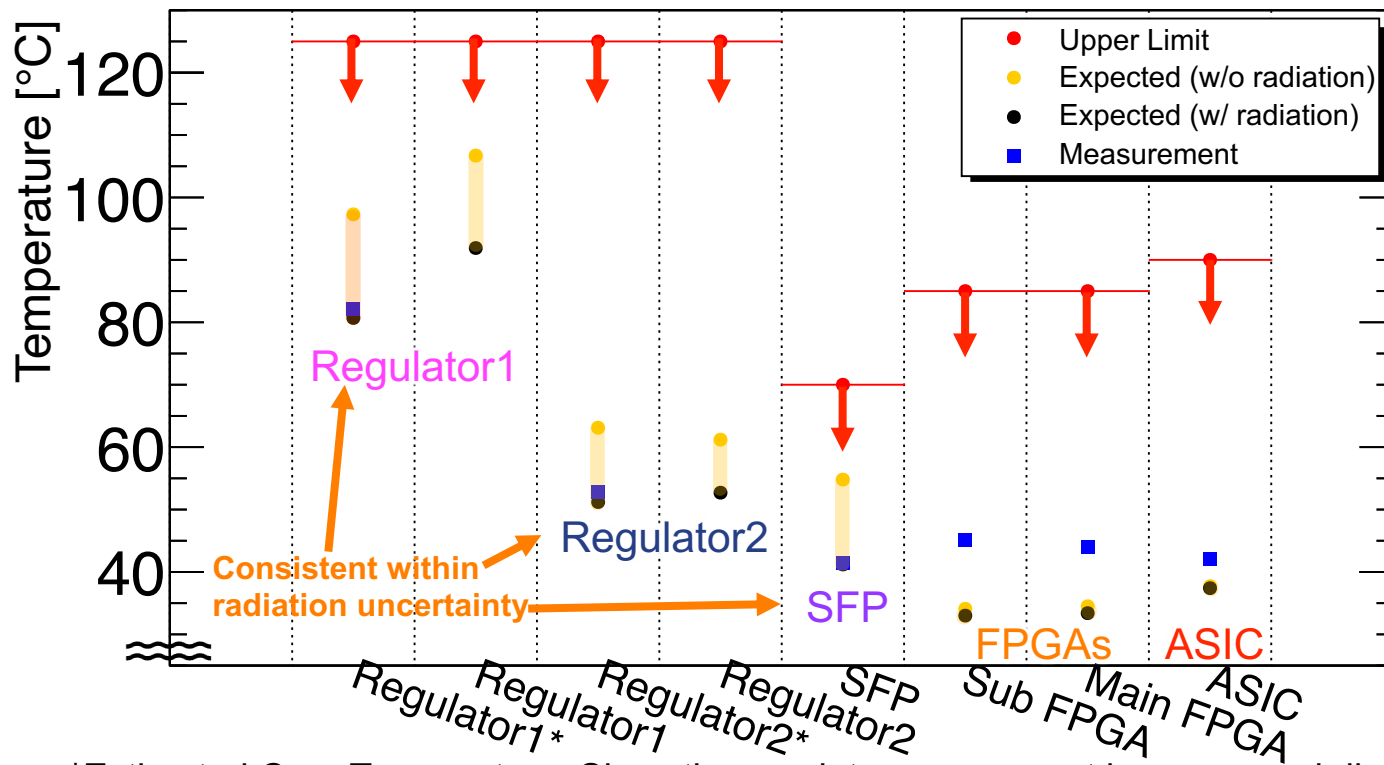
Setup



Validation: Simulation vs. Cooling Test 8/9

- All components confirmed below operational temperature limits
- **Stability $\Delta T = 0.3\text{ }^{\circ}\text{C}$** (0.1 $^{\circ}\text{C}$ chiller control) \ll **Requirement: $8.3\text{ }^{\circ}\text{C}$**
- Data-Simulation discrepancies are acceptable due to sufficient margins
 - Major uncertainty source identified as thermal contact resistance (currently using tape)

▼ Measured vs. Predicted Temperatures in Test Setup



*Estimated Core Temperature: Since the regulator core cannot be measured directly, values are calculated based on measured PCB surface temperatures

Summary and Future Prospect

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Cooling System Validation

- Successful cooling test for the J-PARC muon g-2/EDM experiment
- **Thermal safety verified: All ICs maintained well below operational limits**
 - Data-Simulation discrepancies are acceptable due to sufficient margins (Major uncertainty source identified as thermal contact)

Thermal Stability

- **Thermal stability: ± 0.3 °C achieved**
 - Significantly exceeds the **8.3 °C requirement** for deformation control

Future Prospect

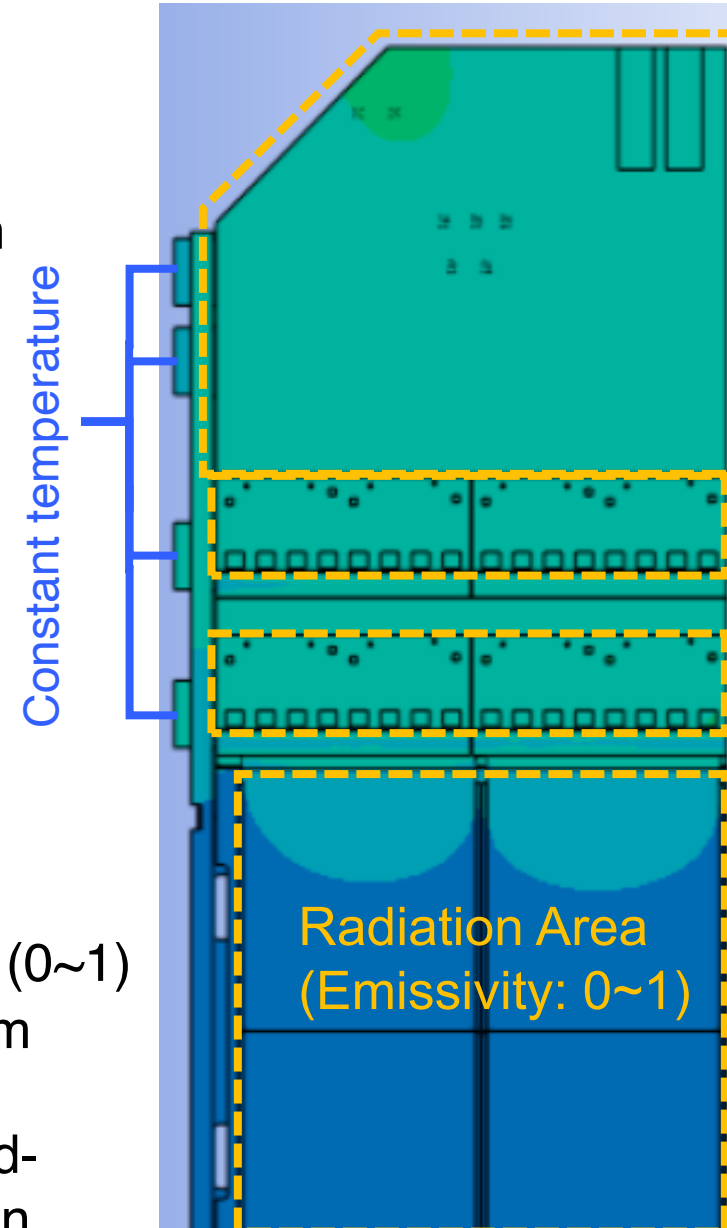
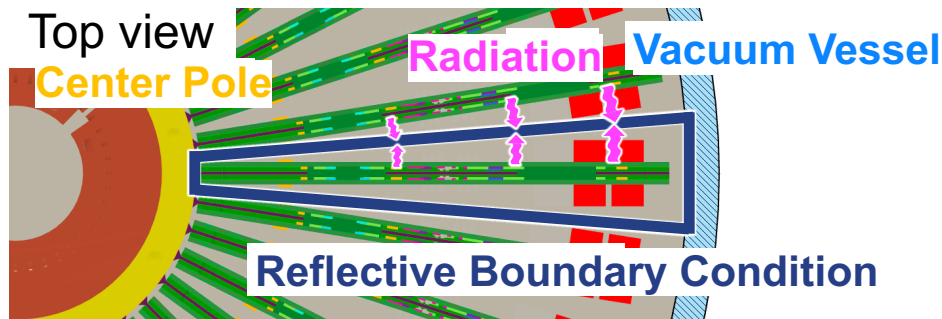
- Design Optimization: **Enhancing Thermal Symmetry**
 - To align Mirror-Side cooling performance with Normal-side, optimize component layout (FPGA/DC-DC)
- Reliability & Error Analysis
 - **Next Step:** Comprehensive cooling test with full-scale integration (FPGA + 32 ASICs + DC-DC) & Long-term stability (1–2 days)
 - Analyze systematic errors in EDM measurements caused by thermal deformation to further improve accuracy

Simulation Setup (ANSYS)

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Boundary Conditions

- **Heat Load:** Calculated from measured power consumption
- **Heat Pipe:** Constant temperature based on independent measurements
- **Radiation:** Applied to large-area boards
- **Environment:** 40-Vane radial configuration modeled with face-to-face radiation

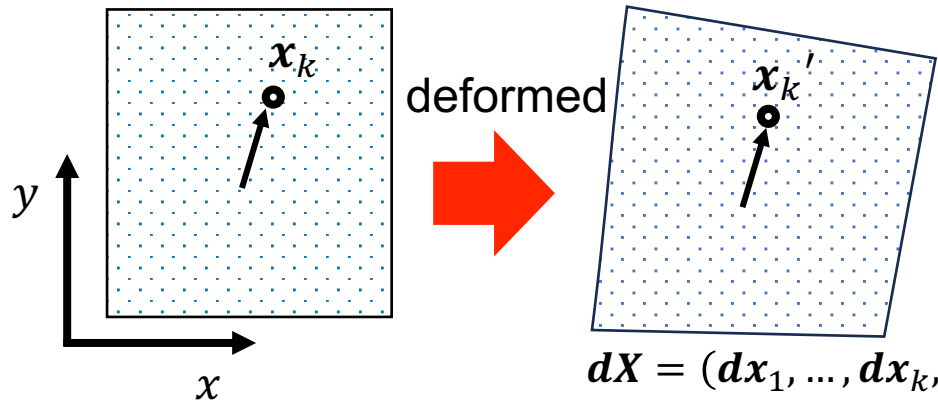


Uncertainties

- **Emissivity:** Accounted for over the full range (0~1)
- **Sensor Position:** ± 1 °C uncertainty per 5 mm displacement
- **Convection (0.1 atm):** Not modeled, but hand-calculated to be less significant than radiation

Deformation analysis

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Position of N points: $X = (x_1, \dots, x_k, \dots, x_N)$

$$x'_k = x_k + dx_k$$

$$X' = X + dX$$

Extract the rotational component that affects the EDM

$$dX = (dx_1, \dots, dx_k, \dots, dx_N)$$

$$dX = \sum a_i e_i = a_{\text{rot}} e_{\text{rot}} + \dots, \quad a_{\text{rot}} = dX \cdot e_{\text{rot}}$$

... consists of orthonormal components (next leading order)

■ Rotation of all vanes ($x \rightarrow x \cos \theta - y \sin \theta$, $y \rightarrow y \cos \theta + x \sin \theta$)

$$\theta \ll 1 \rightarrow \theta dx_{\text{rot}k} = \theta \begin{pmatrix} -y_k \\ x_k \end{pmatrix}, \quad \sqrt{\sum (x_k^2 + y_k^2)} = |dX_{\text{rot}}|$$

$$e_{\text{rot}} = \frac{(dx_{\text{rot}1}, \dots, dx_{\text{rot}k}, \dots, dx_{\text{rot}N})}{|dX_{\text{rot}}|} = \frac{dX_{\text{rot}}}{|dX_{\text{rot}}|}$$

$$a_{\text{rot}} = dX \cdot e_{\text{rot}} = \frac{\sum (-dx_k y_k + dy_k x_k)}{|dX_{\text{rot}}|},$$

$$\theta_{\text{rot}} dX_{\text{rot}} = a_{\text{rot}} e_{\text{rot}} = a_{\text{rot}} \frac{dX_{\text{rot}}}{|dX_{\text{rot}}|},$$

$$\theta_{\text{rot}} = \frac{a_{\text{rot}}}{|dX_{\text{rot}}|}$$

Physically meaningful value

Deformation analysis

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- Requirement of alignment (fake EDM < 10^{-21} ecm)
 - Vane plane rotation θ_{rot} (XY): 10 μrad \Leftrightarrow 2 μm
 - Vane thickness rotation (Z): 200 μrad \Leftrightarrow 40 μm

	Requirements	Uniform temp. +10 °C	Uniform temp. +30 °C	Real (w/ radiation) ~+15 °C	Real (w/o radiation) +30 °C
X	2 μm	~6 μm	~20 μm	~10 μm	~17 μm
Y	2 μm	~12 μm	~40 μm	~27 μm	~37 μm
Z	40 μm	~3 μm	~10 μm	~13 μm	~20 μm
θ_{rot}	10 μrad	2.4 μrad	8.5 μrad	6.2 μrad	14.7 μrad

- Preliminary systematic error estimated from simulation

Error source	10^{-21} [$e \cdot \text{cm}$]
Misalignment	0.6 (6.2 μrad)
Axial E-field	10^{-3} ($E_z=1$ mV/cm)
Radial B-field	10^{-5} ($E_z=1$ mV/cm)
Statistics	1.4 ($5.7 \times 10^{11} e^+$)
Total	1.5

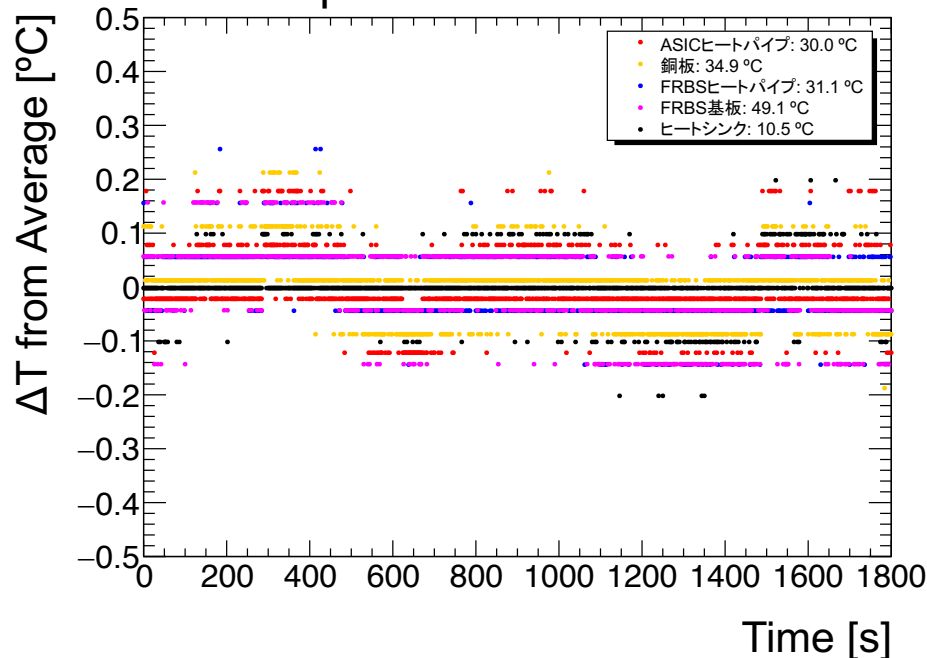
- The systematics of the real operation should be updated based on measurements (temperature, alignment system)

Measurement of Thermal Stability

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Confirmed temperature stability for all components for 30 minutes after reaching thermal equilibrium

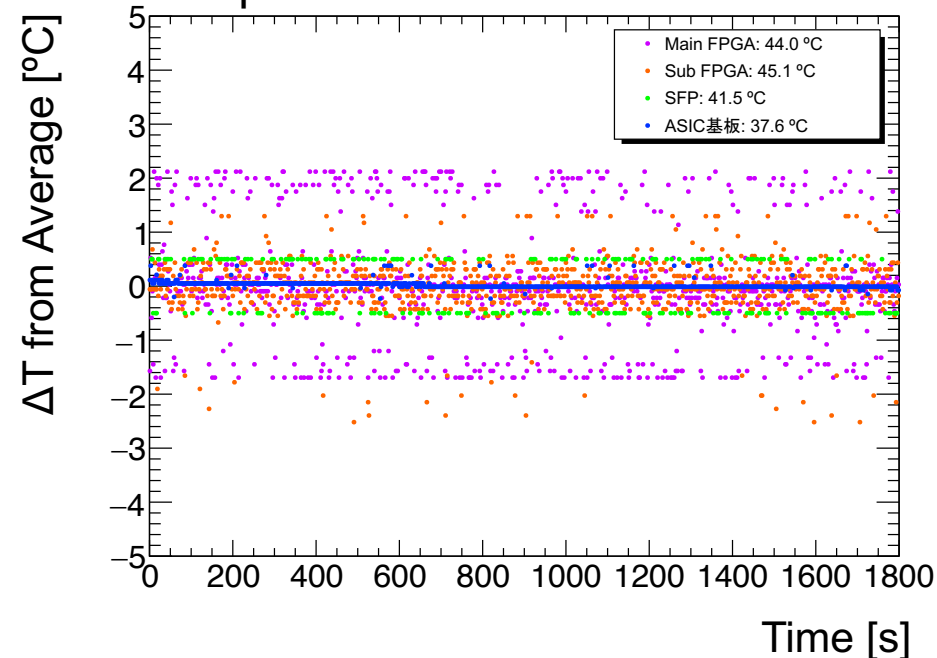
▼ Thermocouples



Stability within 0.3 °C

(Heat sink shows periodic 0.1 °C chiller control cycle)

▼ Temperature IC



Fluctuations are within its sensor precision
(FPGA: 4 °C, SFP: 3 °C, ASIC: 1 °C)

■ Stability under Constant Load: ≤ 0.3 °C maintained

- Verified that heat load is independent of hit rate

■ Expected to satisfy the 8.3 °C system stability requirement

- Non-heating sensors will follow the high stability confirmed in other components

Analysis plan for convection

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- **It is necessary to examine whether convection affects the temperature distribution:** A key dimensionless number for determining whether temperature differences can induce convection in a fluid is the **Rayleigh number**.

Rayleigh number:
$$Ra = \frac{g\beta\Delta TL^3}{\nu a}$$

g : gravitational acceleration, β : thermal expansion coefficient

ΔT : temperature difference (assume 40 °C), L : characteristic length (assume 1 m)

ν : kinematic viscosity $\propto 1/P$, a : thermal diffusivity $\propto 1/P$

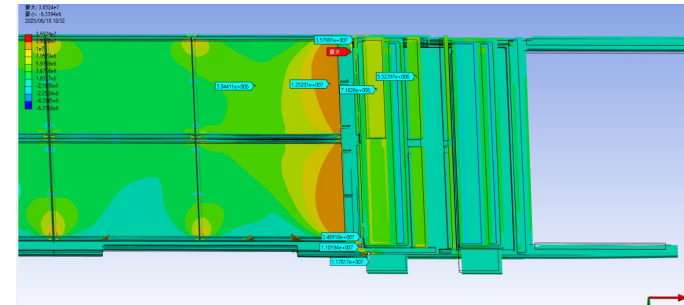
1. Conduction-dominated: $Ra < 1708$
 2. Laminar convection: $Ra \geq 10^4$, heat transfer coefficient: $h = \frac{0.59k}{L} \times (Ra)^{\frac{1}{4}}$ [W/Km²]
 3. Turbulent convection: $Ra \geq 10^9$, heat transfer coefficient: $h = \frac{0.10k}{L} \times (Ra)^{\frac{1}{3}}$ [W/Km²]
- 0.1 atm (10 kPa): $Ra = 4 \times 10^7 \Rightarrow$ convection effect need to be estimated
 - Heat transfer coefficient: $h = 1.2 \text{ W/Km}^2 < \text{Radiation: } h = 6 \sim 7.5 \text{ W/Km}^2$
 - Temperature effects should be estimated by simulation (radiation $\times 1/5 \Rightarrow \sim 4 \text{ °C?}$)
 - 0.0005 atm (50 Pa): $Ra < 1708 \Rightarrow$ no convection effect
 - Consider outgassing, conductance, vacuum pump (coating and baking?)

Preliminary evaluation of stress

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■ Maximum principal stress from simulation:

- Adhesive: ~7 MPa
- Sensor: ~10 MPa
- G10 frame (local): ~37 MPa



■ Stress requirements:

- Adhesive: shear strength ➤ O(10) Mpa: From datasheet
- Silicon, G10: yield strength ➤ O(100) Mpa?: From some papers

The safety factor is ~2, so there may be not so much margin

Future plans for stress evaluation

- Validate parameters such as thermal expansion coefficient and Young's modulus from measurement
- Check actual material strength
- Understand deformation regions with high stress in the simulation
 - Suspect that the lack of spatial margin in the simulation